


<b>Search Notes</b> 	<b>Application/Control No.</b> 10538927	<b>Applicant(s)/Patent Under Reexamination</b> FUJIWARA ET AL.
	<b>Examiner</b> XIAOZHEN XIE	<b>Art Unit</b> 1646

SEARCHED			
Class	Subclass	Date	Examiner
none			

SEARCH NOTES		
Search Notes	Date	Examiner
EAST: USPAT, US-PGPUB, EPO, JPO, DERWENT (see search history)	10/30/2008	XZ
STN: Medline, Embase, Biosis, Caplus, PCTfull (see search history)	10/30/2008	XZ
Inventor names: searched in PALM	10/30/2008	XZ

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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